## Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10658929	LYM, KEVIN
Examiner	Art Unit
Mendoza, Junior O	2423

SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES		
Search Notes	Date	Examiner
Updated EAST Search	1/28/2009	JM
Inventor Search	1/28/2009	JM
http://www.ipdl.inpit.go.jp/homepg_e.ipdl (Japanese Patents)	1/28/2009	JM

	INTERFERENCE SEA	RCH	
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